

# **AO4459**



# P-Channel Enhancement Mode Field Effect Transistor

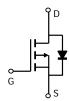
## **General Description**

The AO4459 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  with low gate charge. This device is suitable for use as a load switch or in PWM applications. Standard product AO4459 is Pb-free (meets ROHS & Sony 259 specifications). AO4459L is a Green Product ordering option. AO4459 and AO4459L are electrically identical.

#### **Features**

$$\begin{split} &V_{DS}\left(V\right) = \text{-}30V \\ &I_{D} = \text{-}6.5A \qquad \left(V_{GS} = \text{-}10V\right) \\ &R_{DS(ON)} < 46 \text{m}\Omega \; (V_{GS} = \text{-}10V) \\ &R_{DS(ON)} < 72 \text{m}\Omega \; (V_{GS} = \text{-}4.5V) \end{split}$$





Absolute Maximum Ratings T <sub>A</sub> =25°C unless otherwise noted							
Parameter		Symbol	Maximum	Units			
Drain-Source Voltage		$V_{DS}$	-30	V			
Gate-Source Voltage		$V_{GS}$	±20	V			
Continuous Drain	T <sub>A</sub> =25°C		-6.5				
Current <sup>A</sup>	T <sub>A</sub> =70°C	I <sub>D</sub>	-5.3	Α			
Pulsed Drain Current <sup>B</sup>		I <sub>DM</sub>	-30				
	T <sub>A</sub> =25°C	В	3.1	W			
Power Dissipation A	T <sub>A</sub> =70°C	$-P_{D}$	2	VV			
Junction and Storage Temperature Range		$T_J$ , $T_{STG}$	-55 to 150	°C			

Thermal Characteristics								
Parameter	Symbol	Тур	Units					
Maximum Junction-to-Ambient <sup>A</sup>	t ≤ 10s	В	33	40	°C/W			
Maximum Junction-to-Ambient A	Steady-State	Steady-State $R_{\theta JA}$		75	°C/W			
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{ hetaJL}$	18	24	°C/W			

### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Parameter Conditions		Min	Тур	Max	Units			
STATIC PARAMETERS										
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	I <sub>D</sub> =-250μA, V <sub>GS</sub> =0V				V			
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =-24V, V <sub>GS</sub> =0V				-1				
	Zero Gate Voltage Drain Gunerit		T <sub>J</sub> =55°C			-5	μА			
$I_{GSS}$	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±20V				±100	nA			
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_{D}=-250 \mu A$		-1.5	-1.85	-2.5	V			
$I_{D(ON)}$	On state drain current	V <sub>GS</sub> =-10V, V <sub>DS</sub> =-5V		-30			Α			
R <sub>DS(ON)</sub>		$V_{GS}$ =-10V, $I_{D}$ =-6.5A			38	46	mΩ			
	Static Drain-Source On-Resistance		T <sub>J</sub> =125°C		53	68	11152			
		$V_{GS}$ =-4.5V, $I_D$ =-5A		58	72	mΩ				
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =-5V, I <sub>D</sub> =-6.5A			11		S			
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =-1A,V <sub>GS</sub> =0V			-0.78	-1	V			
$I_S$	Maximum Body-Diode Continuous Current					-3.5	Α			
DYNAMIC	PARAMETERS									
C <sub>iss</sub>	Input Capacitance				668	830	pF			
C <sub>oss</sub>	Output Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =-15V, f=1MHz			126		pF			
$C_{rss}$	Reverse Transfer Capacitance				92		pF			
$R_g$	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz			6	9	Ω			
SWITCHI	NG PARAMETERS									
$Q_g(10V)$	Total Gate Charge (10V)				12.7	16	nC			
Q <sub>g</sub> (4.5V)	Total Gate Charge (4.5V)				6.4		nC			
$Q_{gs}$	Gate Source Charge				2		nC			
$Q_{gd}$	Gate Drain Charge		]		4		nC			
t <sub>D(on)</sub>	Turn-On DelayTime				7.7		ns			
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =-10V, $V_{DS}$ =-15V, $R_L$ =2.5 $\Omega$ , $R_{GEN}$ =3 $\Omega$			6.8		ns			
t <sub>D(off)</sub>	Turn-Off DelayTime				20		ns			
t <sub>f</sub>	Turn-Off Fall Time				10		ns			
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =-6.5A, dI/dt=100A/μs			22	30	ns			
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =-6.5A, dI/dt=100A/μs		-	15		nC			

A: The value of  $R_{\theta JA}$  is measured with the device mounted on  $1in^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25°C. The value in any a given application depends on the user's specific board design. The current rating is based on the t \le 10s thermal resistance rating.

Rev0 Sept 2006

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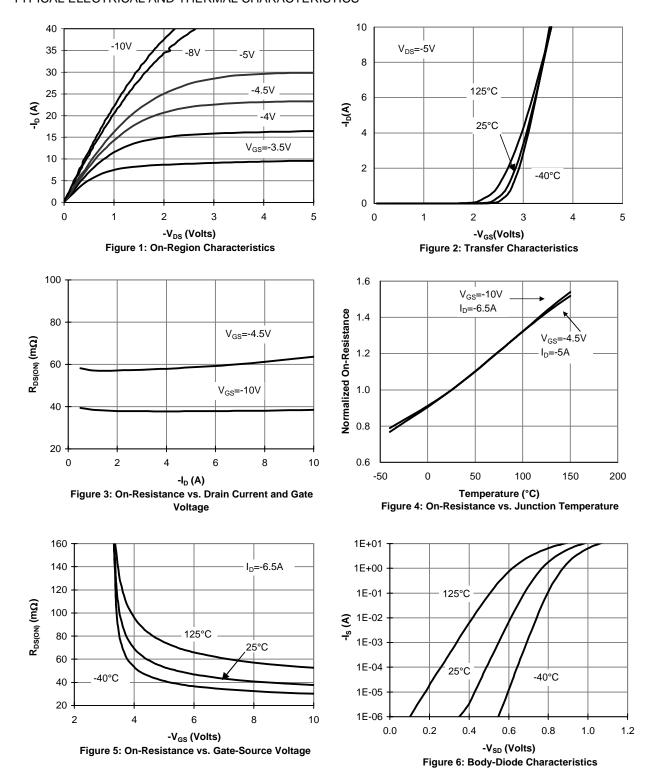
B: Repetitive rating, pulse width limited by junction temperature.

C. The R  $_{\theta JA}$  is the sum of the thermal impedence from junction to lead R $_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using  $< 300 \mu s$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$ =25°C. The SOA curve provides a single pulse rating.

### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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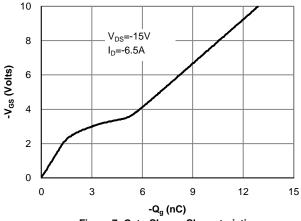


Figure 7: Gate-Charge Characteristics

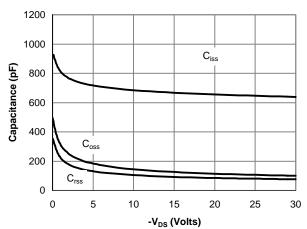


Figure 8: Capacitance Characteristics

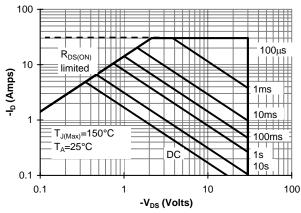


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

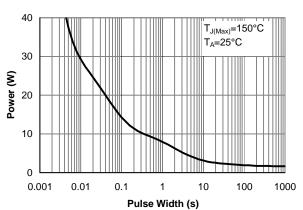


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

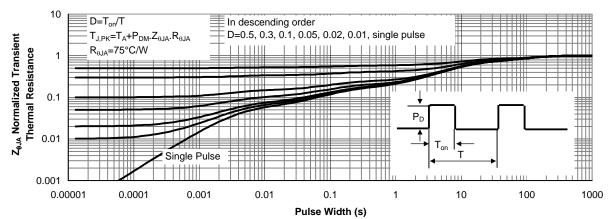


Figure 11: Normalized Maximum Transient Thermal Impedance(Note E)